

Directional Emission from Metal-Dielectric-Metal Structures: Effect of Mixed Metal Layers, Dye Location and Dielectric Thickness

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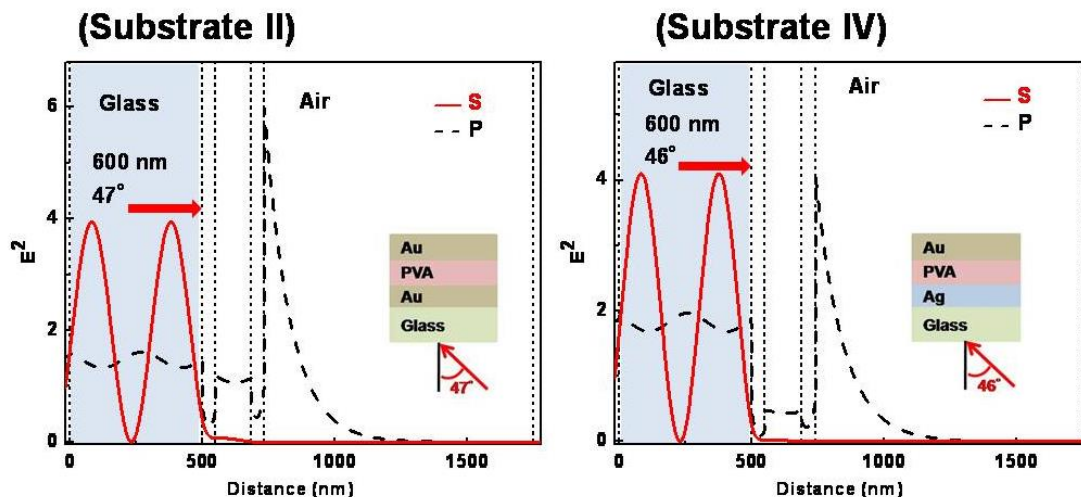


Figure S1. Calculated electric field intensities in MDM substrate II and IV for 600 nm illumination at the respective resonance angles; S-polarized (red) and P-polarized (black).

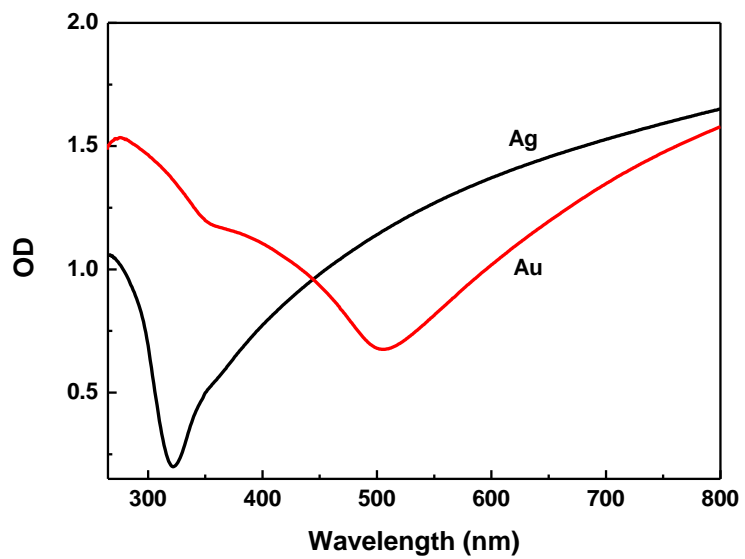


Figure S2. Extinction spectra of 50 nm Ag and Au films deposited on glass slide.

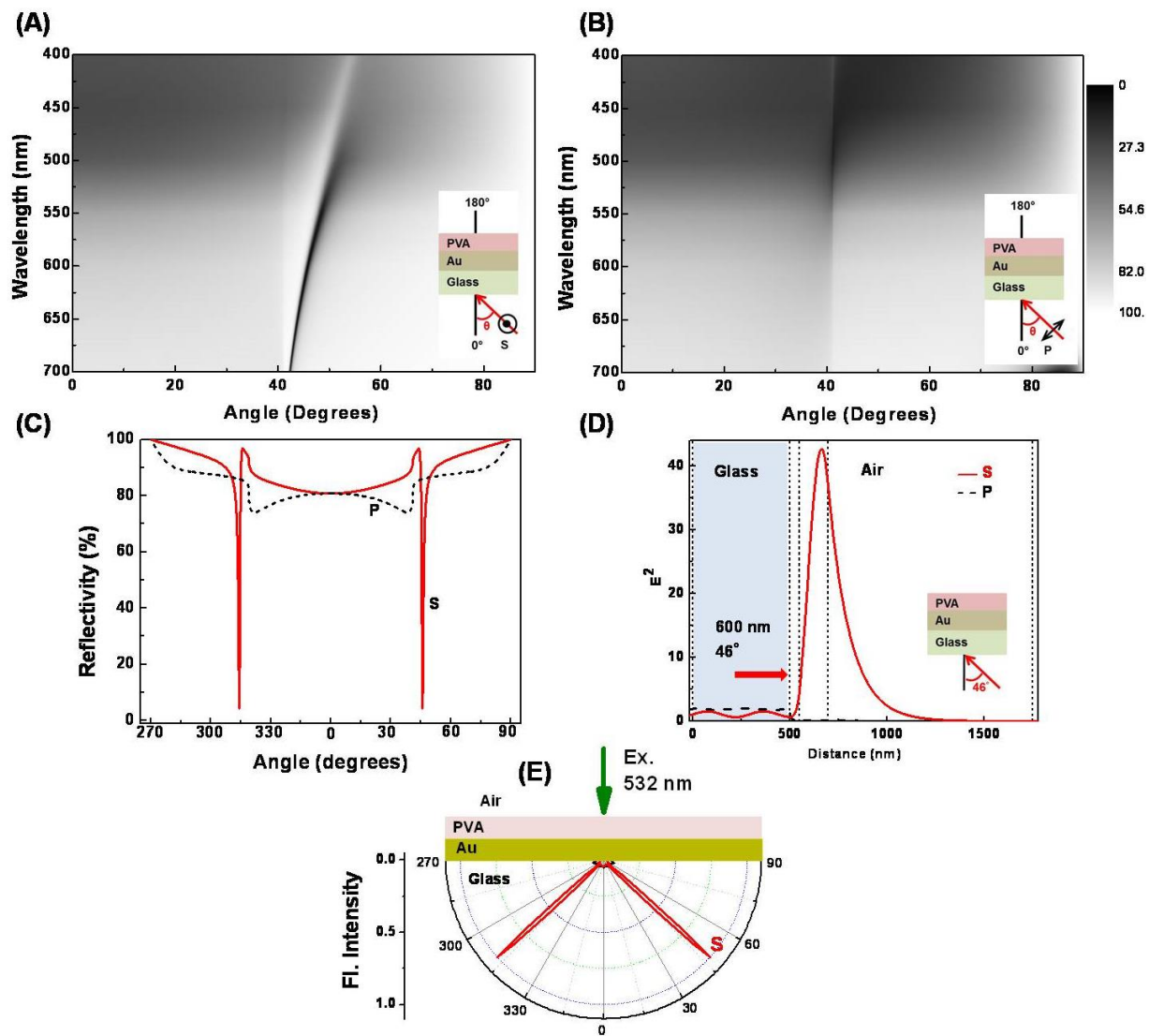


Figure S3. Calculated reflectivity dispersion diagrams, $R(\lambda, \theta)$, for S-polarized (A) and P-polarized illumination in the PVA-Au-glass MD substrate (B), angle-dependent reflectivity with 600 nm incident light (C), electric field intensity for 600 nm illumination (S- and P-polarized) at the reflectivity minimum of 46° (D) and experimentally observed angle-dependent emission intensities at 600 nm from S101 embedded in the PVA layer, PVA thickness 150 nm (E).

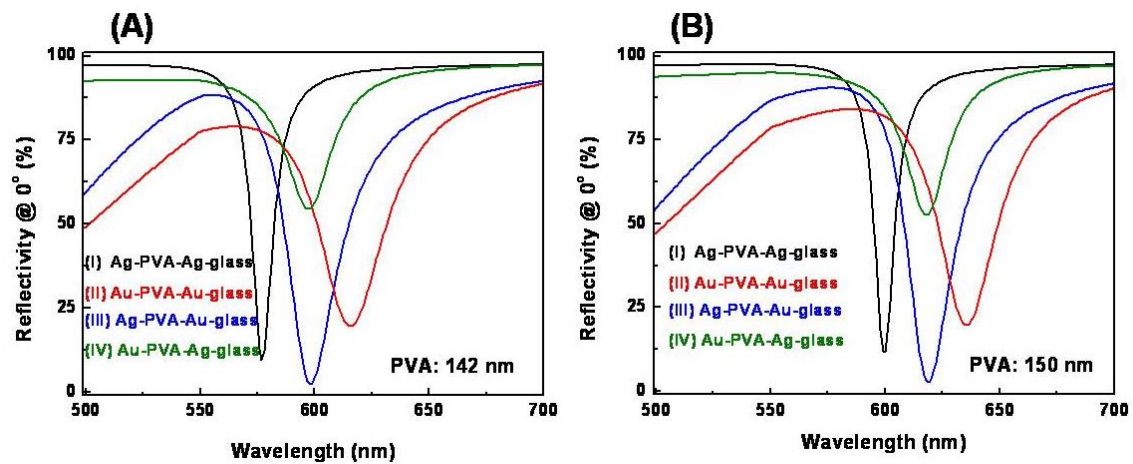


Figure S4. Wavelengths at which the reflectivity dip at 0° is obtained in different MDM substrates for PVA thickness of 142 nm (A) and 150 nm (B).